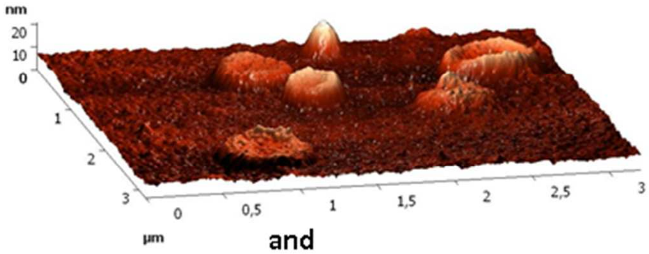
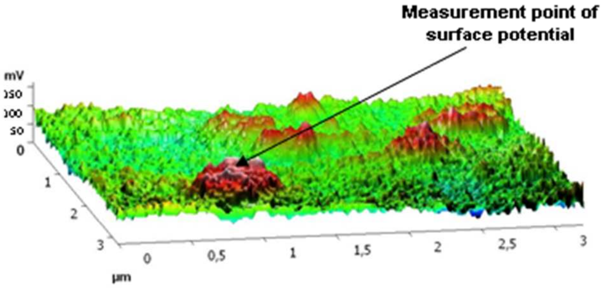
Simultaneous

Atomic force microscopy

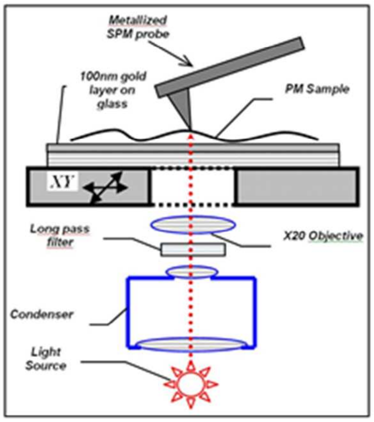


and

Kelvin probe force microscopy



Experimental setup



Surface potential measurement in the dark and upon illumination